NEC

MOS FIELD EFFECT TRANSISTOR

2SK3434

SWITCHING
N-CHANNEL POWER MOS FET
INDUSTRIAL USE

DESCRIPTION

The 2SK3434 is N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

- Super low on-state resistance
  $R_{DS(on)1}$ = 20 mΩ MAX. (V_{GS} = 10 V, I_D = 24 A)
  $R_{DS(on)2}$ = 31 mΩ MAX. (V_{GS} = 4.0 V, I_D = 24 A)
- Low C_{iss}: C_{iss} = 2100 pF TYP.
- Built-in gate protection diode

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3434	TO-220AB
2SK3434-S	TO-262
2SK3434-ZJ	TO-263
2SK3434-Z	TO-220SMD[Note]

Note TO-220SMD package is produced only in Japan.

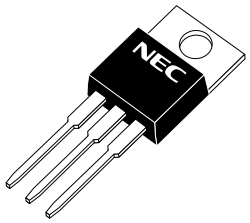
ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Drain to Source Voltage	V_{DSS}	60	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	$I_{D(DC)}$	±48	A
Drain Current (pulse) [Note1]	$I_{D(pulse)}$	±120	A
Total Power Dissipation (T_C = 25°C)	P_T	56	W
Total Power Dissipation (T_A = 25°C)	P_T	1.5	W
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	–55 to +150	°C
Single Avalanche Current [Note2]	I_{AS}	28	A
Single Avalanche Energy [Note2]	E_{AS}	78	mJ

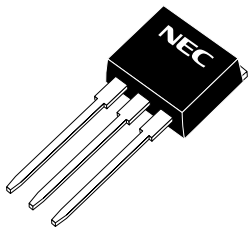
Notes 1. PW ≤ 10 μs, Duty cycle ≤ 1%

2. Starting T_{ch} = 25°C, R_G = 25 Ω, V_{GS} = 20 → 0 V

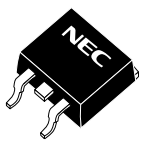
(TO-220AB)



(TO-262)



(TO-263,TO-220SMD)



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The mark ★ shows major revised points.

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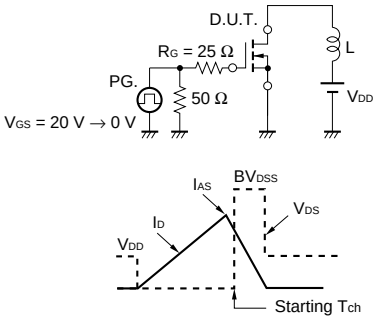
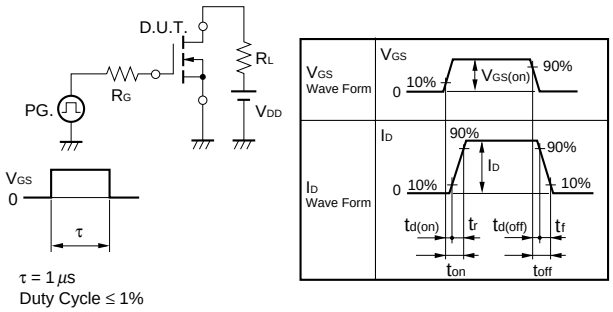
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Drain Current	I_{DSS}	V_{DS} = 60 V, V_{GS} = 0 V			10	μA
Gate Cut-off Voltage	$V_{GS(off)}$	V_{DS} = 10 V, I_D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	$\|y_{fs}\|$	V_{DS} = 10 V, I_D = 24 A	13	27		S
Drain to Source On-state Resistance	$R_{DS(on)1}$	V_{GS} = 10 V, I_D = 24 A		16	20	mΩ
	$R_{DS(on)2}$	V_{GS} = 4.0 V, I_D = 24 A		22	31	mΩ
Input Capacitance	C_{iss}	V_{DS} = 10 V		2100		pF
Output Capacitance	C_{oss}	V_{GS} = 0 V		340		pF
Reverse Transfer Capacitance	C_{rss}	f = 1 MHz		170		pF
Turn-on Delay Time	$t_{d(on)}$	V_{DD} = 30 V, I_D = 24 A		40		ns
Rise Time	t_r	$V_{GS(on)}$ = 10 V		400		ns
Turn-off Delay Time	$t_{d(off)}$	R_G = 10 Ω		120		ns
Fall Time	t_f			160		ns
Total Gate Charge	Q_G	V_{DD} = 48 V		40		nC
Gate to Source Charge	Q_{GS}	V_{GS} = 10 V		7		nC
Gate to Drain Charge	Q_{GD}	I_D = 48 A		11		nC
Body Diode Forward Voltage	$V_{F(S-D)}$	I_F = 48 A, V_{GS} = 0 V		1.0		V
Reverse Recovery Time	t_{rr}	I_F = 48 A, V_{GS} = 0 V		43		ns
Reverse Recovery Charge	Q_{rr}	di/dt = 100 A/μs		61		nC

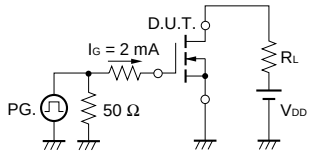
TEST CIRCUIT 1 AVALANCHE CAPABILITY



TEST CIRCUIT 2 SWITCHING TIME

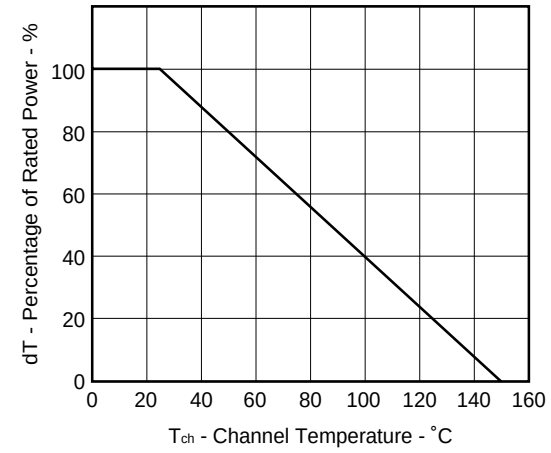


TEST CIRCUIT 3 GATE CHARGE

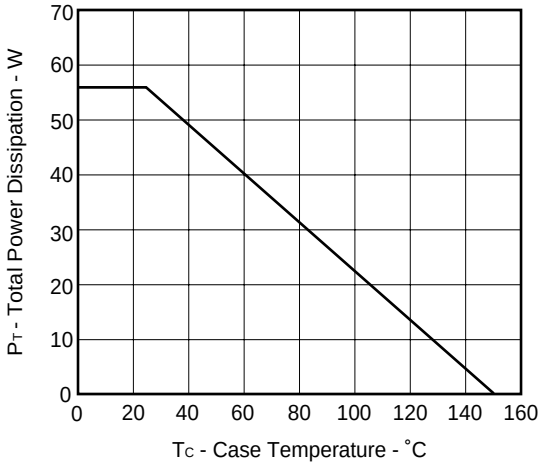


TYPICAL CHARACTERISTICS (T_A = 25°C)

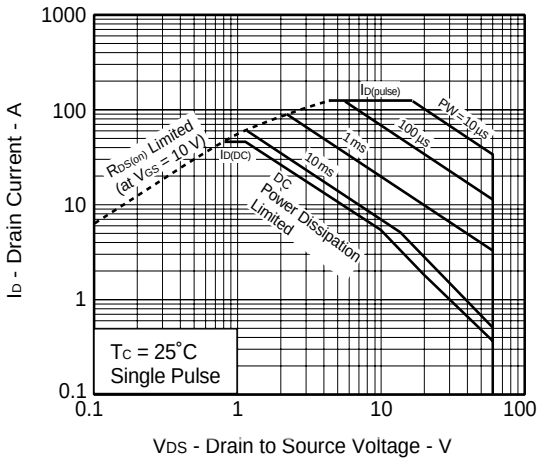
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



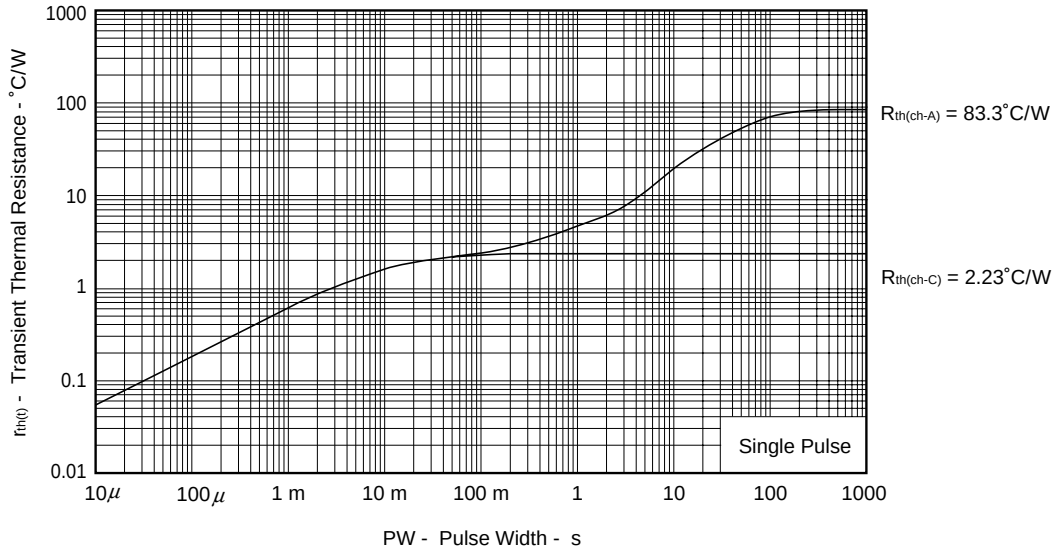
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



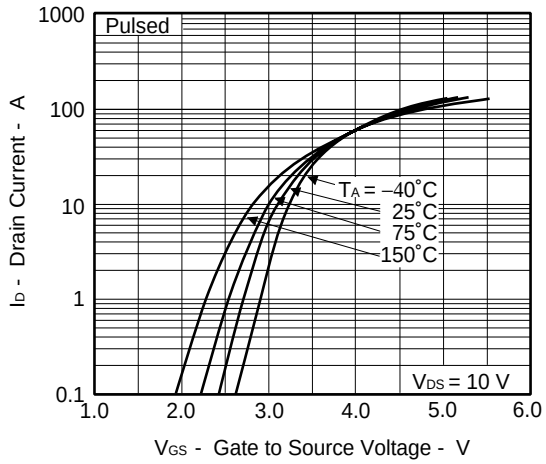
★ FORWARD BIAS SAFE OPERATING AREA



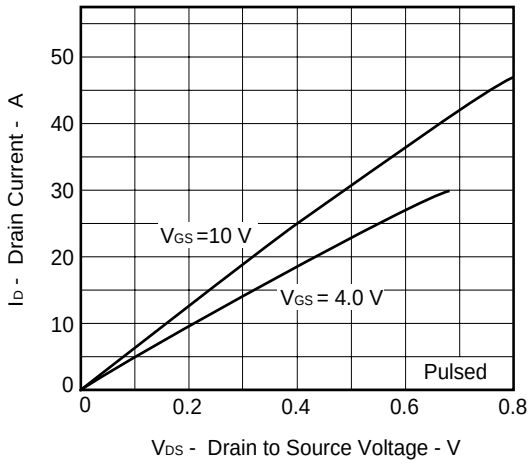
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



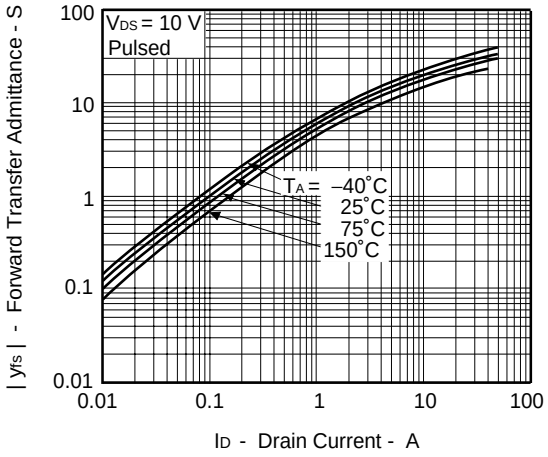
FORWARD TRANSFER CHARACTERISTICS



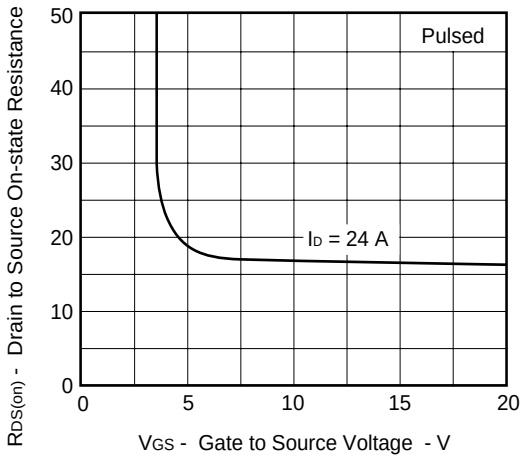
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



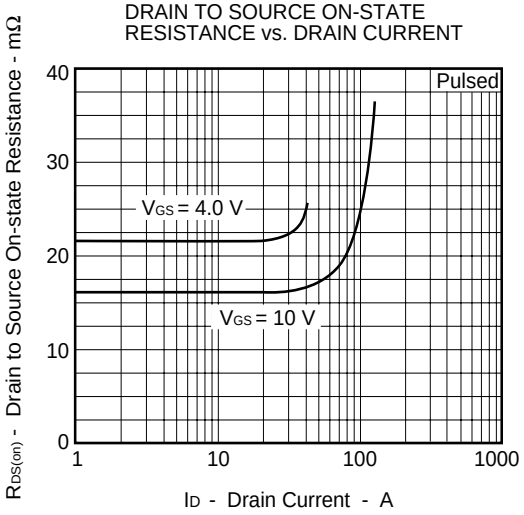
FORWARD TRANSFER ADMITTANCE vs.
DRAIN CURRENT



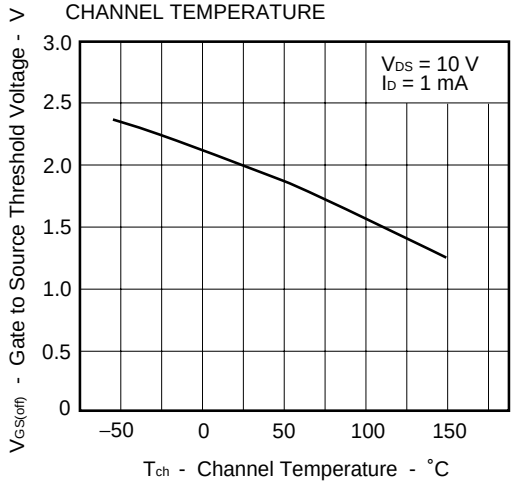
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
GATE TO SOURCE VOLTAGE



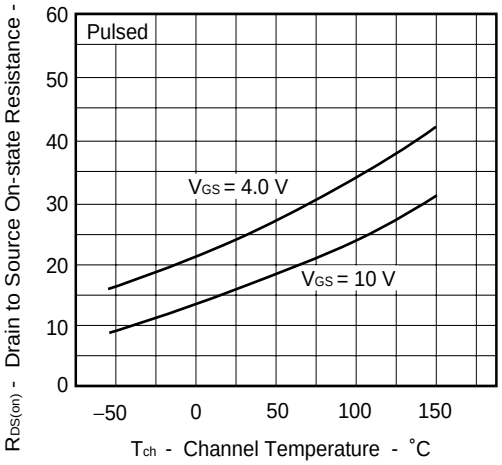
DRAIN TO SOURCE ON-STATE
RESISTANCE vs. DRAIN CURRENT



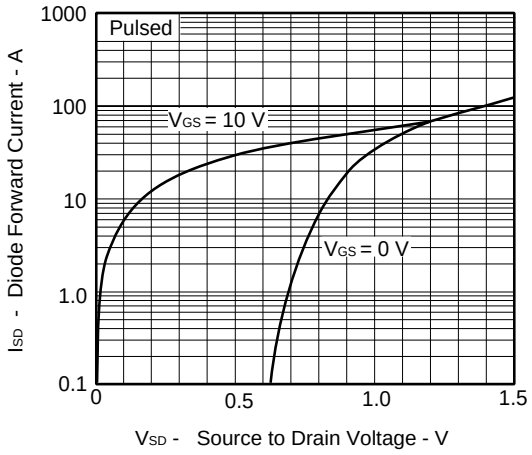
GATE TO SOURCE THRESHOLD VOLTAGE vs.
CHANNEL TEMPERATURE



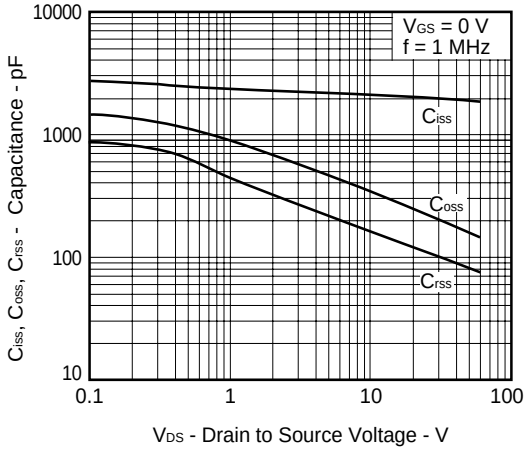
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



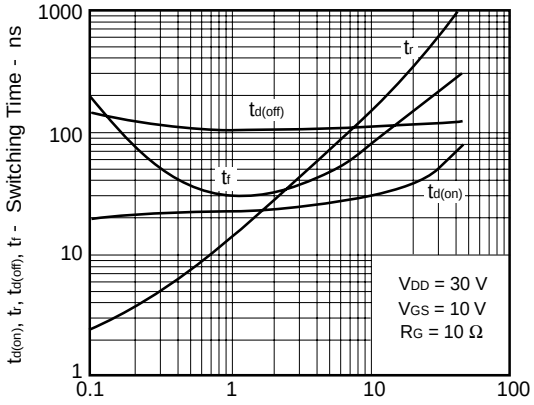
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



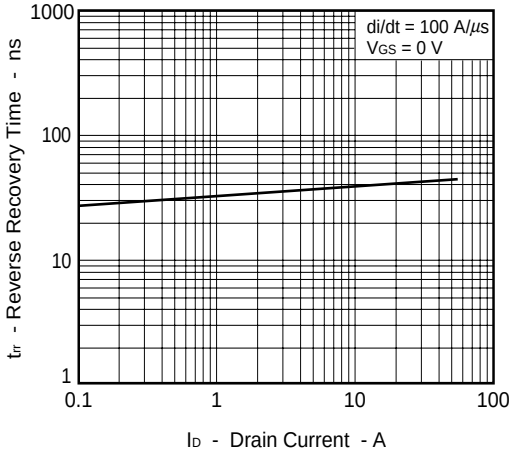
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



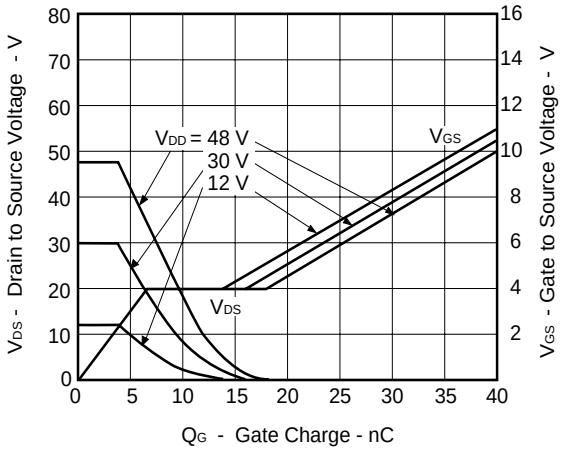
SWITCHING CHARACTERISTICS



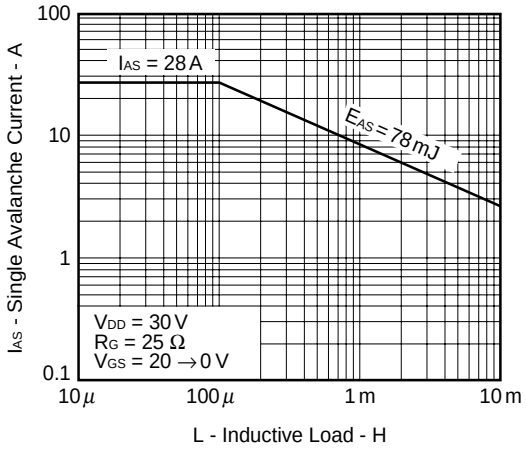
REVERSE RECOVERY TIME vs. DRAIN CURRENT



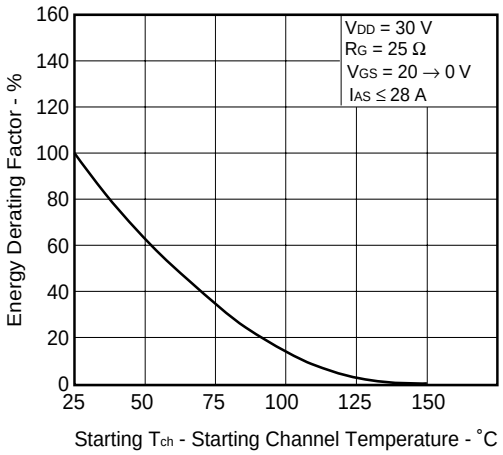
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SINGLE AVALANCHE CURRENT vs.
INDUCTIVE LOAD

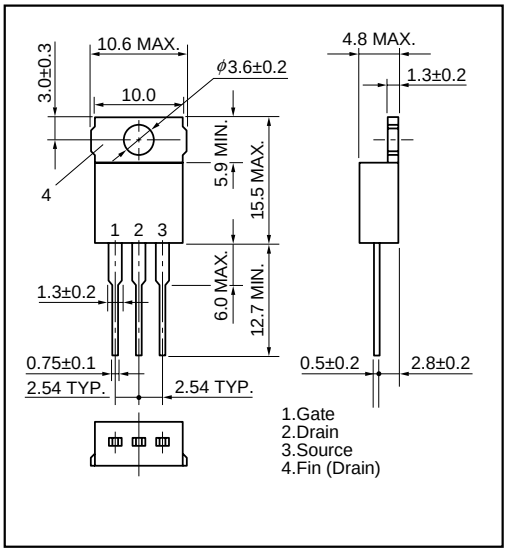


SINGLE AVALANCHE ENERGY
DERATING FACTOR

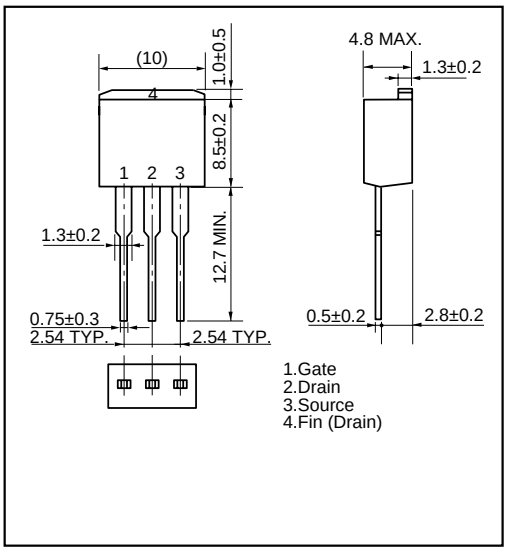


PACKAGE DRAWINGS (Unit: mm)

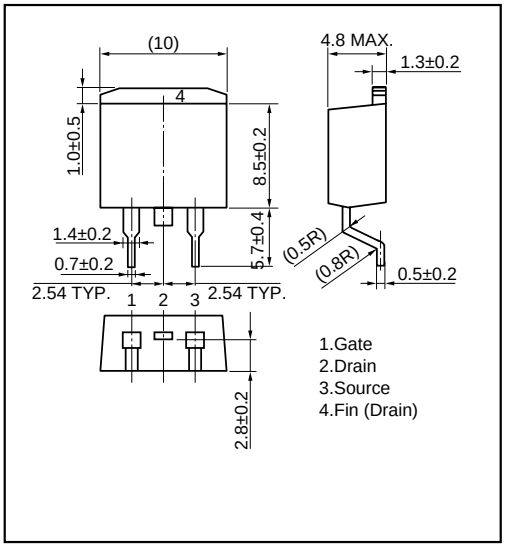
1) TO-220AB(MP-25)



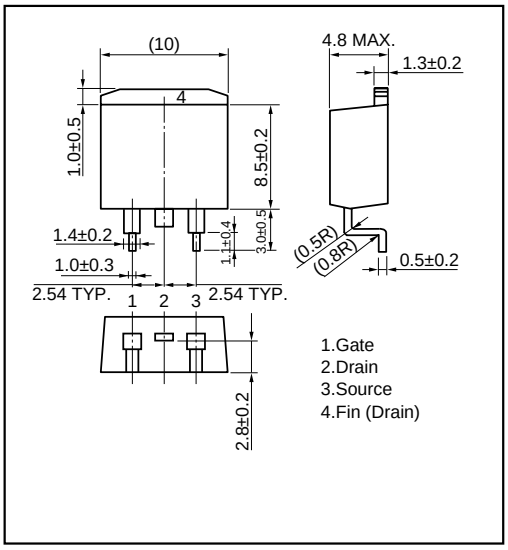
2) TO-262(MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)

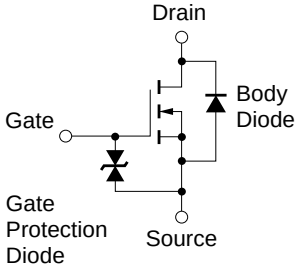


4) TO-220SMD(MP-25Z)[Note]



Note This package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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